



INFORMATION DISCLOSURE CITATION IN AN APPLICATION <small>(Use several sheets if necessary)</small>					ATTY. DOCKET NO. 0171-1026P		APPLICATION NO. 10/679,264		
					APPLICANT OKAZAKI, Satoshi et al.				
					FILING DATE October 7, 2003		GROUP 1773		
U. S. PATENT DOCUMENTS									
EXAMINER INITIAL	DOCUMENT NUMBER	Kind	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
EPJ	US 5,605,776	A	1997-02-25	Isao et al.					
	US 5,714,285	A	1998-02-03	Tu et al.					
	US 5,952,128	A	1999-09-14	Isao et al.					
	US 6,335,124	B1	2002-01-01	Mitsui et al.					
V	US 2002/0058186	A1	2002-05-16	Nozawa et al.					
CPJ	US 2002/0086220	A1	2002-07-04	Nozawa et al.					
CPJ	US 2002/0122991	A1	2002-09-05	Shiota et al.					
	US								
	US								
	US								
FOREIGN PATENT DOCUMENTS									
EXAMINER INITIAL	OFFICE	DOCUMENT NUMBER	Kind	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
CPJ	PCT	WO 94/11786	A1	1994-05-26	PCT			YES	NO
OTHER DOCUMENTS (Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.)									
Yoshioka et al., "An attenuated phase-shifting mask with a single-layer absorptive shifter", Mitsubishi Denki Giho, 1995, Japan, Vol. 69, No. 3, pp. 67-71 (XP 008030088)									
[Redacted]									
[Redacted]									
[Redacted]									
[Redacted]									
EXAMINER <i>Elizabeth D. Vey</i>					DATE CONSIDERED <i>6/5/05</i>				
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